



Radiation Effects in Electronics

Guest Editor:

Message from the Guest Editor

Deadline for manuscript
submissions:
closed (30 September 2021)

This Special Issue aims at clearly describing these contexts and presenting the solutions that must be adopted to ensure the required reliability and functional safety. Submissions are expected to focus on the theoretical aspects, experimental results issued from tests of advanced integrated circuits, benefits, and weaknesses of existing or new fault tolerance strategies. New ideas proposing disruptive approaches are also welcome.

Topics of interest include but are not limited to the following areas:

- Evidence of weaknesses to radiation effects of very advanced circuits;
- Results of accelerated radiation tests on integrated circuits issued from ultimate technologies;
- Results of real-life experiments performed in the Earth's atmosphere;
- Fault tolerance techniques at different levels: hardware, software, architecture;
- Radiation effects on autonomous and connected vehicles;
- Radiation effects on power devices for electric vehicles and green and reusable energy;
- Potential impact of radiation effects on the Internet of Things (IoT) era;





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, Embase, CAPlus / SciFinder, and other databases.

Journal Rank: JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)

Contact Us

Applied Sciences Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/applsci
applsci@mdpi.com
[X@Applsci](https://twitter.com/Applsci)